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**Prabhat Verma
Alexander Egner**
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Contents

v *Conference Committee*

FAR-FIELD IMAGING

- 8815 04 ***In vivo* photoacoustic imaging of breast cancer tumor with HER2-targeted nanodiamonds** [8815-3]
T. Zhang, H. Cui, The Univ. of Kansas (United States); C.-Y. Fang, Institute of Atomic and Molecular Science (Taiwan); J. Jo, X. Yang, The Univ. of Kansas (United States); H.-C. Chang, Institute of Atomic and Molecular Science (Taiwan); M. L. Forrest, The Univ. of Kansas (United States)

FAR-FIELD SUPER RESOLUTION MICROSCOPY I

- 8815 08 **Image resolution in optical nanoscopy (Invited Paper)** [8815-28]
R. P. J. Nieuwenhuizen, S. Stallinga, B. Rieger, Technische Univ. Delft (Netherlands)

FAR-FIELD SUPER RESOLUTION MICROSCOPY II

- 8815 0D **Cryogenic localization of single molecules with angstrom precision (Invited Paper)** [8815-12]
S. Weisenburger, Max Planck Institute for the Science of Light (Germany); B. Jing, A. Renn, ETH Zurich (Switzerland); V. Sandoghdar, Max Planck Institute for the Science of Light (Germany)
- 8815 0G **Localization microscopy for the study of amyloid fibril formation** [8815-15]
D. Pinotsi, G. S. Kaminski Schierle, E. Rees, C. F. Kaminski, Univ. of Cambridge (United Kingdom)

SURFACE-ENHANCED SPECTROSCOPY I

- 8815 0K **Raman spectroscopy for intracellular localisation of meso-tetraphenylporphyrin-gold nanoparticles conjugates** [8815-19]
R. Al-Majmaie, Univ. College Dublin (Ireland) and Univ. of Baghdad (Iraq); N. Alattar, E. Kennedy, M. Al-Rubeai, J. H. Rice, D. Zerulla, Univ. College Dublin (Ireland)

TIP-ENHANCED SPECTROSCOPY/MICROSCOPY I

- 8815 00 **A new technique for fabrication of better metallic nanotips for nanoimaging through tip-enhanced Raman spectroscopy** [8815-23]
T. Umakoshi, Osaka Univ. (Japan); T. Yano, Tokyo Institute of Technology (Japan); Y. Saito, P. Verma, Osaka Univ. (Japan)

NEAR-FIELD SCANNING OPTICAL MICROSCOPY

- 8815 0R **Super resolution mapping of the near optical field and the gradient optical force** [8815-25]
R. M. Gelfand, A. Bonakdar, O. G. Memis, H. Mohseni, Northwestern Univ. (United States)
- 8815 0S **Numerical modeling of scattering type scanning near-field optical microscopy** [8815-26]
A. Ravichandran, E. C. Kinzel, Missouri Univ. of Science and Technology (United States); J. C. Ginn, Plasmonics Inc. (United States); J. A. D'Archangel, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States); E. Z. Tucker, The Univ. of North Carolina at Charlotte (United States); B. A. Lail, Florida Institute of Technology (United States); M. B. Raschke, Univ. of Colorado at Boulder (United States); G. D. Boreman, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States) and The Univ. of North Carolina at Charlotte (United States)

ENHANCED SPECTROSCOPY AT METALLIC-GAP

- 8815 19 **Critical importance of nanogaps between metal nanoparticles and metal substrates in surface enhanced Raman scattering (Invited Paper)** [8815-43]
M. Futamata, S. Handa, H. Suzuki, H. Chiba, Saitama Univ. (Japan)

Author Index

Conference Committee

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Xiaowei Zhuang, Harvard University (United States)

Session Chairs

- 1 Far-Field Imaging
Jörg Enderlein, Georg-August-Universität Göttingen (Germany)

- 2 Far-Field Super Resolution Microscopy I
Prabhat Verma, Osaka University (Japan)
- 3 Far-Field Super Resolution Microscopy II
Alexander Egner, Laser-Laboratory Göttingen e.V. (Germany)
- 4 Surface-Enhanced Spectroscopy I
Siegfried Weisenburger, Max-Planck-Institut für die Physik des Lichts
(Germany)
- 5 Tip-Enhanced Spectroscopy/Microscopy I
Markus B. Raschke, University of Colorado at Boulder (United States)
- 6 Near-Field Scanning Optical Microscopy
Prabhat Verma, Osaka University (Japan)
- 7 Far-Field Super Resolution Microscopy III
Fabien Pinard, The University of Southern California (United States)
- 8 Surface-Enhanced Spectroscopy II
Alexander Egner, Laser-Laboratory Göttingen e.V. (Germany)
- 9 Tip-Enhanced Spectroscopy/Microscopy II
Peter Nordlander, Rice University (United States)
- 10 Enhanced Spectroscopy at Metallic-Gap
Alfred J. Meixner, Eberhard Karls Universität Tübingen (Germany)